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Impact of Threshold Voltage Instability on Static and Switching Performance of GaN Devices with p-GaN Gate

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Citation:

Yang, F., C. Xu, and B. Akin. 2019. "Impact of threshold voltage instability on static and switching performance of GaN devices with p-GaN gate." IEEE Applied Power Electronics Conference and Exposition 2019: 951-957, doi: 10.1109/APEC.2019.8722163

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